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Application No.	10105,663	Prepared by	NH
Examiner-GAU	Vargot-1732	Date	4-13-4
		No. of queries	1
		Tracking Number	05918987
		Week Date	03/15/04
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JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	q. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
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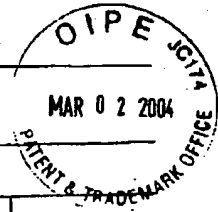
FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
BIF114531SERIAL NO.  
10/015,586**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

37 CFR 1.98(b)

APPLICANT  
Hao-Wen Chiu et al.FILING DATE  
December 17, 2001GROUP  
1722

MAR 02 2004

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,376,317	12/94	MAUS et al.			
	AB	5,458,820	10/95	LEFEBVE			
	AC						
	AD						

**FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION**

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AI	99/24243	05/99	WO			
	AJ	2 525 525	10/83	FR			English abstract
	AK						
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

**OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)**

	AT	
	AU	
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	AX	
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**EXAMINER****DATE CONSIDERED**

**EXAMINER:** Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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